

## In re Application of:

Guy T. Blalock

Serial No.: 10/663,587

Filed: September 16, 2003

For: PLASMA PROBE, METHODS FOR

FABRICATING THE SAME, AND METHODS FOR USING THE SAME

Confirmation No.: Unknown

Examiner: Unknown

Group Art Unit: Unknown

Attorney Docket No.: 2269-4716US

(00-0991.00/US)

#### CERTIFICATE OF MAILING

I hereby certify that this correspondence along with any attachments referred to or identified as being attached or enclosed is being deposited with the United States Postal Service as First Class Mail on the date of deposit shown below with sufficient postage and in an envelope addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

December 2, 2003

Date

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#### INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

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In compliance with the duty to disclose information material to patentability pursuant to 37 C.F.R. § 1.56, it is respectfully requested that this Information Disclosure Statement be entered and the documents listed on attached Form PTO-1449 or PTO/SB/08 be considered by the Examiner and made of record. Copies of the listed documents are enclosed pursuant to 37 C.F.R. § 1.98(a).

In accordance with 37 C.F.R. § 1.97(g) and (h), filing of this Information Disclosure Statement is not to be construed as a representation that a search has been made or an admission that the information cited herein is, or is considered to be, material to patentability as defined in 37 C.F.R. § 1.56(b). Further, no representation is made by Applicant herein that no other possible material information as defined in 37 C.F.R. § 1.56(b) exists.

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## U.S. Patent Documents

U.S. Patent No.	Publication Date	Patentee
US - 5,065,201	11/12/1991	Yamauchi
US - 5,315,145	05/24/1994	Lukaszek
US - 5,594,328	01/14/1997	Lukaszek
US - 6,051,443	04/18/2000	Ghio et al.
US - 6,140,833	10/31/2000	Flietner et al.
US - 6,144,037	11/07/2000	Ryan et al.

### Other Documents

- BOEDO, J., "UCSD-FERP Boundary Diagnostics for NSTX," NSTX PAC Meeting, May 1997, 6 pages.
- "Fast Reciprocating Probes for Edge Profile Characterization on NSTX," January 1998, 1 page.
- LUKASZEK et al., "CHARM: A New Wafer Surface Charge Monitor, TechCon '90, San Jose, 4 pages.
- MOYER, Rick, "Langmuir Probes and Boundary Plasma Measurements," DIII-D News, http://fusion.gat.com/DNT/DNT21.htm, August 1994, 3 pages.
- MOYER, Rick, "UC San Diego Boundary Diagnostics for NSTX," NSTX FY98 Research Forum, December 1997, pp. 1-11.
- MOYER, Rick, "UC San Diego Boundary Diagnostics for NSTX," NSTX FY98 Research Forum, December 1997, pp. 1-12.
- MOYER, Rick, "UC San Diego Fluctuation and Turbulent Transport Diagnostics for NSTX," NSTX FY98 Research Forum, December 1997, pp. 1-8.
- RUDAKOV, D.L. et al., "Probe Diagnostics," http://www.rsphysse.anu.edu.au/prl/probht.html, date unknown, 4 pages.

Applicant offers to supply any explanation or discussion of the documents that the Examiner feels is necessary or desirable and which is requested.

This Information Disclosure Statement is filed within three (3) months of the filing date of the above-identified application, and no certification pursuant to 37 C.F.R. § 1.97(c) or a fee pursuant to 37 C.F.R. § 1.17(p) is required.

Respectfully submitted,

Brick G. Power

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Date: December 2, 2003

BGP/dlm:djp

Enclosures: Form PTO-1449 or PTO/SB/08

Cited Documents

Document in ProLaw

PTO/SB/08A (10-01)

Approved for use through 10/31/2002. OMB 0651-0031

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# INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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of

Sheet

Complete if Known				
Application Number	10/663,587			
Filing Date	September 16, 2003			
First Named Inventor	Guy T. Blalock			
Group Art Unit	Unknown			
Examiner Name	Unknown			
Attorney Docket Number	2269-4716US (00-0991.00/US)	J		

U.S. PATENT DOCUMENTS					
Examiner Cite Initials * No.		Document Number  Number - Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevan Passages or Relevant Figures Appear
		US-5,065,201	11/12/1991	Yamauchi	
		US- 5,315,145	05/24/1994	Lukaszek	<del></del>
	1	US- 5,594,328	01/14/1997	Lukaszek	
		US- 6,051,443	04/18/2000	Ghio et al.	
	1	US- 6,140,833	10/31/2000	Flietner et al.	
		US- 6,144,037	11/07/2000	Ryan et al.	
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FOREIGN PATENT DOCUMENTS						
Examiner			Name of Patentee or	Pages, Columns, Lines,		
Initials*	No.1	Country Code <sup>3</sup> - Number <sup>4</sup> - Kind Code <sup>5</sup> (if known)	Publication Date MM-DD-YYYY	Applicant of Cited Document	Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>
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INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

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Application Number 10/663,587

Filing Date September 16, 2003

First Named Inventor Guy T. Blalock

Group Art Unit Unknown

Examiner Name Unknown

(use as many sheets as necessary)

Sheet 2 of 2 Attorney Docket Number 2269-4716US (00-0991 00/US)

		OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS	
Examiner Initials *	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	Т2
		BOEDO, J., "UCSD-FERP Boundary Diagnostics for NSTX," NSTX PAC Meeting, May 1997, 6 pages.	
		"Fast Reciprocating Probes for Edge Profile Characterization on NSTX," January 1998, 1 page.	
		LUKASZEK et al., "CHARM: A New Wafer Surface Charge Monitor, TechCon '90, San Jose, 4 pages.	
		MOYER, Rick, "Langmuir Probes and Boundary Plasma Measurements," DIII-D News, http://fusion.gat.com/DNT/DNT21.htm, August 1994, 3 pages.	
		MOYER, Rick, "UC San Diego Boundary Diagnostics for NSTX," NSTX FY98 Research Forum, December 1997, pp. 1-11.	
		MOYER, Rick, "UC San Diego Boundary Diagnostics for NSTX," NSTX FY98 Research Forum, December 1997, pp. 1-12.	
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		RUDAKOV, D.L. et al., "Probe Diagnostics," http://www.rsphysse.anu.edu.au/prl/probht.html, date unknown, 4 pages.	

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